



## Product Change Notification - LIAL-21SDJX488

**Date:**

30 May 2018

**Product Category:**

8-bit PIC Microcontrollers; Capacitive Touch Sensors

**Affected CPNs:****Notification subject:**

CCB 3397 Initial Notice: Qualification of MPHL as an additional final test site for selected Atmel products available in 32L VQFN package

**Notification text:****PCN Status:**

Initial notification

**PCN Type:**

Manufacturing Change

**Microchip Parts Affected:**

Please open one of the icons found in the Affected CPNs section above.

**NOTE:** For your convenience Microchip includes identical files in two formats (.pdf and .xls)

**Description of Change:**

Qualification of MPHL as an additional final test site for selected Atmel products available in 32L VQFN package.

**Pre Change:**

Tested at ANAC final test site

**Post Change:**

Tested at MPHL final test site

**Pre and Post Change Summary:**

	Pre Change	Post Change	
<b>Final test site</b>	Amkor Assembly & Test (Shanghai) Co., LTD (ANAC)	Amkor Assembly & Test (Shanghai) Co., LTD (ANAC)	Microchip Technology Operations (Philippines) Corporation (MPHL)

**Impacts to Data Sheet:**

None

**Change Impact:**

None

**Reason for Change:**

To improve on-time delivery performance by qualifying MPHL as an additional final test site.

**Change Implementation Status:**

In Progress

**Estimated Qualification Completion Date:**

August 2018

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the



estimated first ship date guided in the final PCN customers may receive pre and post change parts.

**Time Table Summary:**

Workweek	May 2018					->	August 2018				
	18	19	20	21	22		31	32	33	34	35
Initial PCN Issue Date					X						
Qual Report Availability									X		
Final PCN Issue Date									X		

**Method to Identify Change:**

Traceability code

**Qualification Plan:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual Plan.

**Revision History:**

**May 30, 2018:** Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):**

[PCN\\_LIAL-21SDJX488\\_QUAL\\_PLAN.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

**Terms and Conditions:**

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To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."



**MICROCHIP**

**QUALIFICATION PLAN SUMMARY**

**PCN #: LIAL-21SDJX488**

**Date**

**May 8, 2018**

**Qualification of MPHL as an additional final test site for selected Atmel products available in 32L VQFN package.**

**Purpose:** Qualification of MPHL as an additional final test site for selected Atmel products available in 32L VQFN package.

**CCB No.:** 3397

<b>Test / Evaluation</b>	<b>Test Conditions / Parameters</b>
<b>Site by Site Verification</b>	<ul style="list-style-type: none"><li>• Correct site location from actual vs. OI.</li></ul>
<b>Datalog Comparison</b>	<ul style="list-style-type: none"><li>• Accept if all match or justify the differences</li></ul>
<b>Bin-to-Bin Comparison</b>	<ul style="list-style-type: none"><li>• 100% correlated or explainable</li></ul>
<b>Single-Site Test Time</b>	<ul style="list-style-type: none"><li>• Comparable or explainable</li></ul>
<b>Test Stability</b>	<ul style="list-style-type: none"><li>• 100% pass or explainable</li></ul>
<b>Parametric Test Stability</b>	<ul style="list-style-type: none"><li>• Accept on Cpk &gt; 1.67 or explainable</li></ul>
<b>Correlation Lot Run</b>	<ul style="list-style-type: none"><li>• Accept on yield match within 1% Bin-to-bin difference should be within 0.1%</li></ul>

LIAL-21SDJX488 - CCB 3397 Initial Notice: Qualification of MPHL as an additional final test site for selec

Affected Catalog Part Numbers(CPN)

AT42QT1110-MUR  
AT42QT2100-MUR  
ATMEGA168A-MU  
ATMEGA168A-MUR  
ATMEGA168PA-MN  
ATMEGA168PA-MNR  
ATMEGA168PA-MU  
ATMEGA168PA-MUA1  
ATMEGA168PA-MUR  
ATMEGA168PA-MUR431  
ATMEGA168PA-MURA1  
ATMEGA328-MU  
ATMEGA328-MUR  
ATMEGA328P-MN  
ATMEGA328P-MNR  
ATMEGA328P-MU  
ATMEGA328P-MUR  
ATTINY48-MU  
ATTINY48-MUR  
ATTINY48-MUR522  
ATTINY48-MUR547  
ATTINY861A-MU  
ATTINY861A-MUR  
ATTINY88-MU  
ATTINY88-MUR  
ATTINY88-MURA1